TCC
Nokia

FINAS
Finnish Accreditation Service
T117 (EN ISO/IEC 17025)

HAC T-Coil Signal Test Report

Test report no.:	Salo_HAC_0739_02	**Date of report:**	2007-10-01
Template version:	3.0	**Number of pages:**	26
Testing laboratory:	TCC Salo P.O. Box 86 Joensuunkatu 7H / Kiila 1B FIN-24101 SALO, FINLAND Tel. +358 (0) 7180 08000 Fax. +358 (0) 7180 45220	**Client:**	Nokia Corporation 12278 Scripps Summit Drive SAN DIEGO CA. 92131 USA Tel. +1 858 831 5000 Fax. +1 858 831 6500
Responsible test engineer:	Ari Orte	**Product contact person:**	Bill Griffin
Measurements made by:	Virpi Tuominen		
Tested devices:	RM-257 (Hearing aid mode active)		
FCC ID:	QMNRM-257		
Supplement reports:	Salo_HAC_0739_01		
Testing has been carried out in accordance with:	**ANSI C63.19-2006** American National Standard for Methods of Measurement of Compatibility between Wireless Communications Devices and Hearing Aids		
Documentation:	The documentation of the testing performed on the tested devices is archived for 15 years at TCC Nokia.		
Test results:	**The tested device complies with the requirements in respect of all parameters subject to the test.** The test results and statements relate only to the items tested. The test report shall not be reproduced except in full, without written approval of the laboratory.		

Date and signatures:

For the contents:

Digitally signed
by Ari Orte
Date: 2007.10.01
18:10:11 +03'00'

CONTENTS

1. SUMMARY OF HAC T-COIL SIGNAL TEST REPORT

1.1 Test Details

Period of test	2007-09-21 to 2007-09-24
SN, HW, SW and EUT numbers of tested device	SN: 004401/01/111749/2, HW: 4604, SW: 4.40
Batteries used in testing	BL-4C, EUT: 11546, 11735
State of sample	Prototype unit
Notes	AWF = -5 for GSM, 0 for WCDMA

1.2 Summary of T-Coil Test Results

1.2.1 T-Coil Coupling Field Intensity

1.2.1.1 Axial Field Intensity

Mode	Minimum limit [dB (A/m)]	Result [dB (A/m)]	Verdict
GSM850	-13	0.07	Pass
WCDMA1700/2100	-13	-3.56	Pass
GSM1900	-13	0.03	Pass

1.2.1.2 Radial Field Intensity

Mode	Minimum limit [dB (A/m)]	Minimum Result [dB (A/m)]	Verdict
GSM850	-18	-8.42	Pass
WCDMA1700/2100	-18	-9.17	Pass
GSM1900	-18	-8.45	Pass

1.2.2 Frequency Response at Axial Measurement Point

Mode	Verdict
GSM850	Pass
WCDMA1700/2100	Pass
GSM1900	Pass

1.2.3 Signal Quality

Mode	Minimum limit [dB]				Minimum result [dB]	Category assesment
	T1	T2	T3	T4		
GSM850	-15	-5	5	15	22.8	T4
WCDMA1700/2100	-20	-10	0	10	19.9	T4
GSM1900	-15	-5	5	15	24.7	T4

1.2.4 Overall HAC rating of the tested device

Mode	RF emissions category at T-coil axial measurement point (E- and H-fields)*	Category assessment, T-Coil signal quality	HAC category of the tested device (RF emissions and T-coil requirements combined)
GSM850	M3	T4	M3/T3
WCDMA1700/2100	M4	T4	
GSM1900	M3	T4	

*See separate report Salo_HAC_0739_01

2. DESCRIPTION OF THE EQUIPMENT UNDER TEST (EUT)

Modes of Operation	Bands	Modulation Mode	Duty Cycle	Transmitter Frequency Range (MHz)
GSM	850 1900	GMSK	1/8	824 – 849 1850 – 1910
WCDMA	1700/2100	QPSK	1	1712 - 1753

Outside of USA the transmitter of the device is capable of operating also in 900MHz and 1800MHz bands, which are not part of this filing.

2.1 Picture of Device

See HAC RF Emissions Test Report, Salo_HAC_0739_01.

3. TEST CONDITIONS

3.1 Temperature and Humidity

Ambient temperature (°C):	19.3 to 22.2
Ambient humidity (RH %):	39 to 57

3.2 WD Control

The transmitter of the device was put into operation by using a call tester. Communications between the device and the call tester were established by air link. Speech coding was processed with EFR speech codec for GSM and with AMR 12.2 kbps for WCDMA.

The device output power was set to maximum power level for all tests; a fully charged battery was used for every test sequence.

In all operating bands the measurements were performed on middle channel.

3.3 WD Parameters

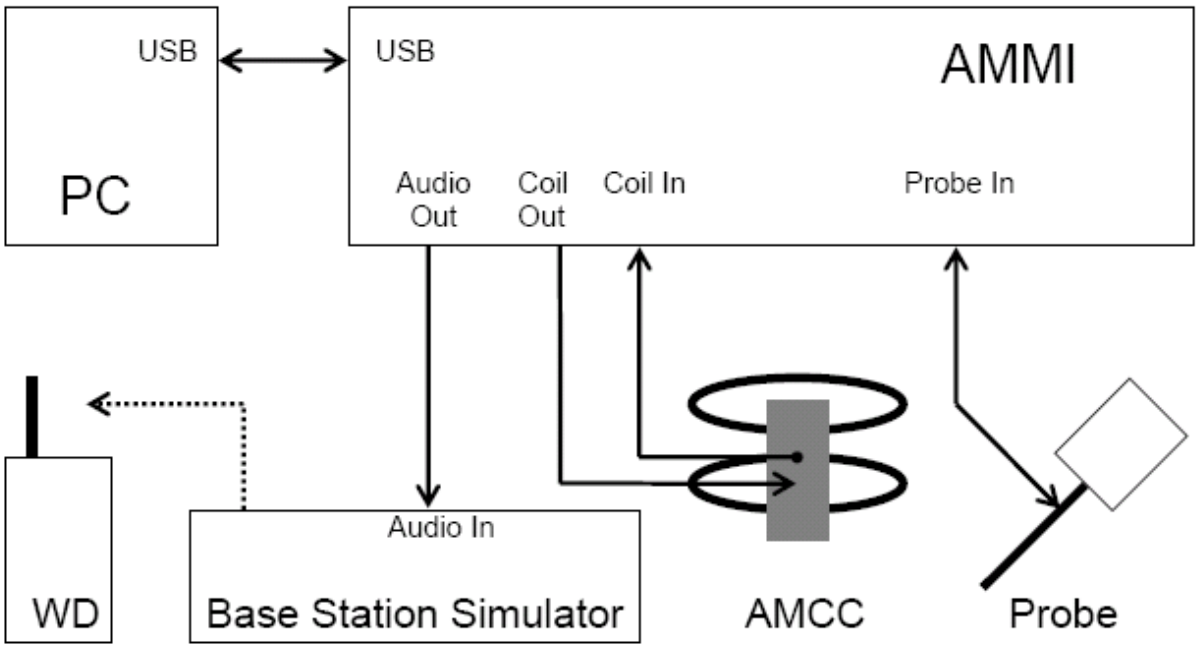
HAC mode was switched on from the WD user interface, volume setting was set to maximum and microphone was muted.

4. DESCRIPTION OF THE TEST EQUIPMENT

4.1 Measurement system and components

The measurements were performed using an automated near-field scanning system, DASY 4 software version 4.7, manufactured by Schmid & Partner Engineering AG (SPEAG) in Switzerland.

Components and signal paths of used measurement system are pictured below:



The following table lists calibration dates of measurement equipment:

Test Equipment	Serial Number	Calibration interval	Calibration expiry
DAE4	555	12 months	2008-03
R&S CMU200 Radio Communication Test Set	101111	12 months	2008-07
AM1DV3 Audio Magnetic Probe	3036	12 months	2008-02
AMMI Audio Magnetic Measurement Instrument	1002	-	-
AMCC Helmholtz Audio Magnetic Calibration Coil	1004	-	-

4.1.1 Audio Magnetic Probe AM1DV3

Construction	Fully RF shielded metal construction (RF sensitivity < -100dB)
System calibration	Calibrated using Helmholtz coil according to manufacturers instructions
Frequency range	0.1 – 20 kHz (HOX! test signal is limited to required BW of 300 to 3000 Hz, ANSI C63.19)
Sensitivity	< -50 dB A/m
Dimensions	Overall length: 290 mm; Tip diameter: 6 mm

4.1.2 Audio Magnetic Measurement Instrument AMMI

Sampling Rate	48 kHz / 24 bit
Dynamic Range	85 dB
Test Signal Generation	User selectable and predefined (via PC)
System calibration	Auto-calibration / full system calibration using AMCC with monitor output

4.1.3 Audio Magnetic Calibration Coil AMCC

Dimensions	370 x 370 x 196 mm (ANSI-C63.19 compliant)

4.1.4 Device Holder

The device holder and Test Arch are manufactured by Speag (http://www.dasy4.com/hac). Test arch is used for all tests i.e. for both validation testing and device testing. The holder and test arch conforms to the requirements of ANSI C63.19.

The SPEAG device holder (see Section 5.1) was used to position the test device in all tests.

4.2 Verification of the System

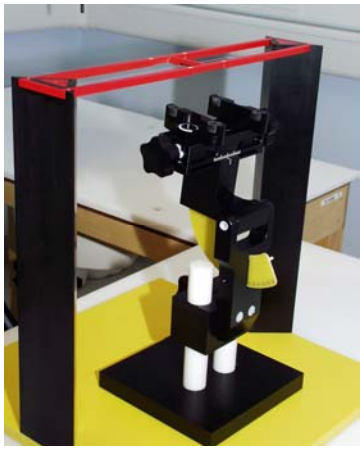
Audio Magnetic Probe AM1D is calibrated in AMCC Helmholtz Audio Magnetic Calibration Coil before each measurement procedure using calibration and reference signals.

R&S CMU200 audio codec and SPEAG AMMI audio paths (gain) were calibrated according to manufacturer's instructions.

5. DESCRIPTION OF THE TEST PROCEDURE

5.1 Test Arch and Device Holder

The test device was placed in the Device Holder (illustrated below) that is supplied by SPEAG. Using this positioner the tested device is positioned under Test Arch.



Device holder and Test Arch supplied by SPEAG

5.2 Test Positions

The device was positioned such that Device Reference Plane was touching the bottom of the Test Arch. The acoustic output is aligned with the intersection of the Test Arch's middle bar and dielectric wire. The WD is positioned always this way to ensure repeatability of the measurements. Coordinate system depicted below is used to define exact locations of measurement points relative to the center of the acoustic output.

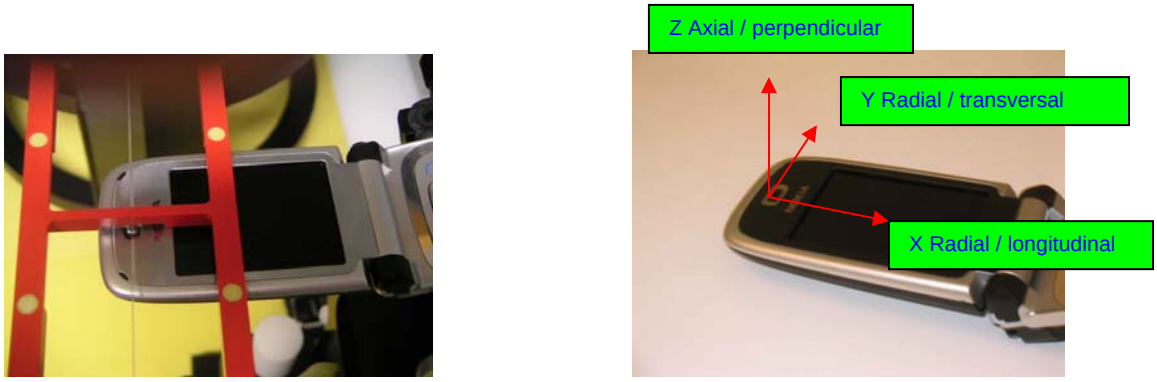


Photo of the device positioned under Test Arch and coordinate system (The EUT in picture is generic phone sample and does not represent the actual equipment under test)

5.3 T-coil Scan Procedures

Manufacturer can either define measurement locations for WD categorization or optimum locations can be found using following procedure; First, coarse scans in all measurement orientations, centered at the earpiece, are made to find approximate locations of optimum signal. More accurate fine scans are made in these locations to find final measurement points.

5.4 Measurement procedure and used test signals

During measurements signal is fed to WD via communication tester. Proper gain setting is used in software to ensure correct signal level fed to communication tester speech input. Measurement software compares fed signal and signal from measurement probe and applies proper filtering and integration procedures.

Broadband voice-like signal (300...3000Hz) is used during scans and frequency response measurement to ensure proper operation of WD vocoder and audio enhancement algorithms.

Both signal (ABM1) and undesired audio noise (ABM2) are measured consequently to enable determination of signal+noise to noise ratio (SNR).

In final measurement sine signal is used to determine signal strength @ 1025 Hz.

5.5 T-coil Requirements and Category Limits

RF Emissions

Wireless device has to fulfill RF emission requirements at the axial measurement location.

Axial Field Intensity

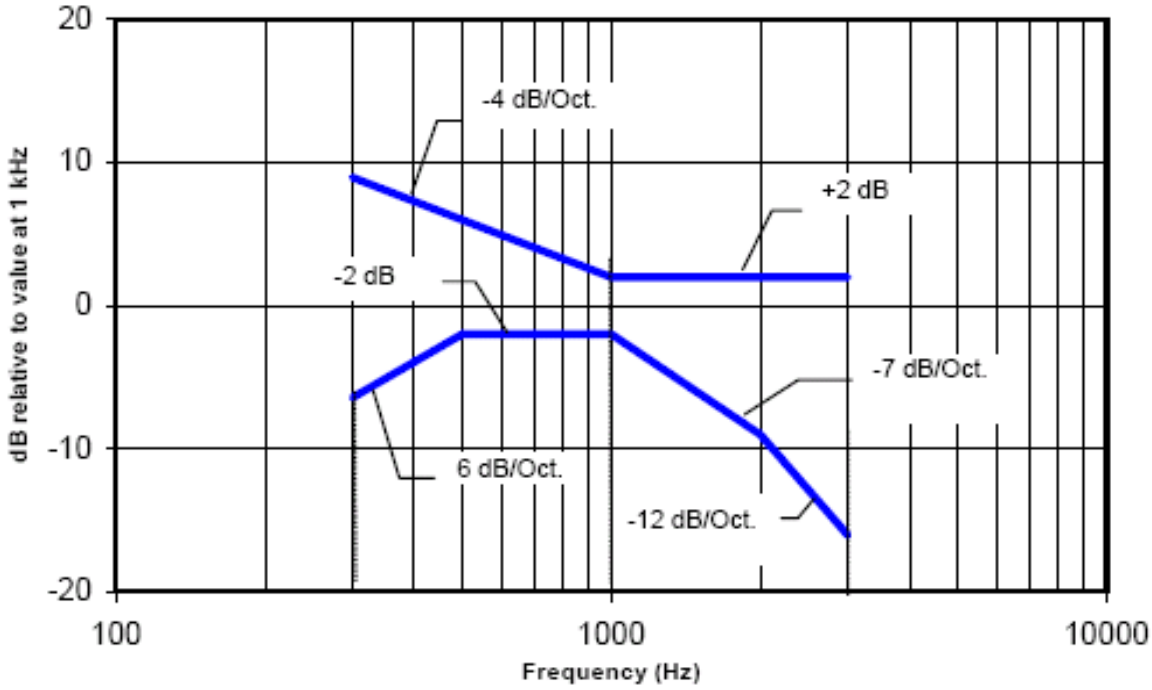
The axial component of the magnetic field shall be ≥-13dB(A/m) at 1 kHz, in 1/3 octave band filter.

Radial Field Intensity

The radial components of the magnetic field shall be ≥-18dB(A/m) at 1 kHz, in 1/3 octave band filter.

Frequency Response

Frequency response of the axial component must be between the limits pointed by frequency curves below:



Frequency response window applicable for devices with axial field strength > -10dB(A/m)

Signal Quality

The worst result of three T-coil signal measurements is used to define WD Hearing Aid T-category according to the category limits:

Category	AWF [dB]	Limits for Signal Quality [dB]
T1	0	-20
	-5	-15
T2	0	-10
	-5	-5
T3	0	0
	-5	5
T4	0	10
	-5	15

6. MEASUREMENT UNCERTAINTY

Source of Uncertainty	Tolerance ±%	Probability Distribution	Div.	c ABM1	c ABM2	Standard Uncertainty ±%, ABM1	Standard Uncertainty ±%, ABM2
PROBE SENSITIVITY							
Reference level	3.0	N	1.0	1	1	3.0	3.0
AMCC geometry	0.4	R	√3	1	1	0.2	0.2
AMCC current	0.6	R	√3	1	1	0.4	0.4
Probe positioning during calibration	0.1	R	√3	1	1	0.1	0.1
Noise contribution	0.7	R	√3	0.0143	1	0.0	0.4
Frecuency slope	5.9	R	√3	0.1	1.0	0.3	3.5
PROBE SYSTEM							
Repeatability / Drift	1.0	R	√3	1	1	0.6	0.6
Linearity / Dynamic range	0.6	R	√3	1	1	0.4	0.4
Acoustic noise	1.0	R	√3	0.1	1	0.1	0.6
Probe angle	2.3	R	√3	1	1	1.4	1.4
Spectral processing	0.9	R	√3	1	1	0.5	0.5
Integration time	0.6	N	1.0	1	5	0.6	3.0
Field disturbation	0.2	R	√3	1	1	0.1	0.1
TEST SIGNAL							
Reference signal spectral response	0.6	R	√3	0	1	0.0	0.4
POSITIONING							
Probe positioning	1.9	R	√3	1	1	1.1	1.1
Phantom thickness	0.9	R	√3	1	1	0.5	0.5
EUT Positioning	1.9	R	√3	1	1	1.1	1.1
EXTERNAL CONTRIBUTIONS							
RF interference	0.0	R	√3	1	1	0.0	0.0
Test singnal variation	2.0	R	√3	1	1	1.2	1.2
COMBINED UNCERTAINTY							
Combined Standard Uncertainty (ABM field)						4.1	6.1
Expanded Standard Uncertainty [%]						**8.1**	**12.3**

7. RESULTS

Measurement location coordinates are defined as deviation from earpiece center in millimeters. Coordinate system is defined in chapter 4.2

Axial measurement location was defined by the manufacturer of the device as the center of the earpiece. Maximum values for axial field are listed for informative purposes although results at earpiece center were used in evaluating T-category of the device.

GSM 850 results

	Radial 1 (longitudinal)		Radial 2 (transversal)		Axial			
					Max signal		Earpiece	
	x	y	x	y	x	y	x	y
Measurement location (x,y) [mm]	5.4	6.0	0.4	0.2	-0.4	5.8	0	5
Signal strength [dB A/m]	-8.42		-8.23		0.26		0.07	
ABM2 [dB A/m]	-33.8		-31.0		-33.4		-37.9	
Signal quality [dB]	25.4		22.8		33.7		38.0	
Ambient background noise at point (0,0) ABM [dB A/m]	-54.3		-54.3		-54.4			

WCDMA 1700/2100 results

	Radial 1 (longitudinal)		Radial 2 (transversal)		Axial			
					Max signal		Earpiece	
	x	y	x	y	x	y	x	y
Measurement location (x,y) [mm]	5.8	7	0.6	0.4	-0.4	6.2	0	5
Signal strength [dB A/m]	-9.17		-8.79		-0.44		-3.56	
ABM2 [dB A/m]	-50.9		-28.7		-43.4		-44.0	
Signal quality [dB]	41.7		19.9		42.9		40.4	
Ambient background noise at point (0,0) ABM [dB A/m]	-44.5		-42.4		-43.9			

GSM 1900 results

	Radial 1 (longitudinal)		Radial 2 (transversal)		Axial			
					Max signal		Earpiece	
	x	y	x	y	x	y	x	y
Measurement location (x,y) [mm]	5.4	6.2	0.4	0	-0.2	5.8	0	5
Signal strength [dB A/m]	-8.45		-8.25		0.27		0.03	
ABM2 [dB A/m]	-35.6		-33.0		-41.6		-41.6	
Signal quality [dB]	27.2		24.7		41.9		41.6	
Ambient background noise at point (0,0) ABM [dB A/m]	-43.6		-42.1		-42.8			

Plots of the signal strength measurement scans are presented in Appendix A.

APPENDIX A: MEASUREMENT SCANS

Date/Time: 2007-09-21 13:48:13
Test Laboratory: TCC Nokia
Type: RM-257; EUT: 12239; Serial: 004401/01/111749/2

Communication System: GSM850
Frequency: 836.6 MHz
Medium: Air
Medium parameters used: σ = 0 mho/m, ε_r = 1; ρ = 1 kg/m^3
Phantom section: AMB with Coil Section

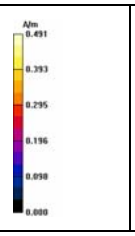
DASY4 Configuration:
- Probe: AM1DV3 - 3036; Probe Notes: Sensitivity .007364 V / A/m
- Calibrated: 2007-02-16
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn555; Calibrated: 2007-03-15
- Phantom: HAC Test Arch with Coil; Type: SD HAC P01 BA; Serial: 1004
- Measurement SW: DASY4, V4.7 Build 53; Postprocessing SW: SEMCAD, V1.8 Build 172

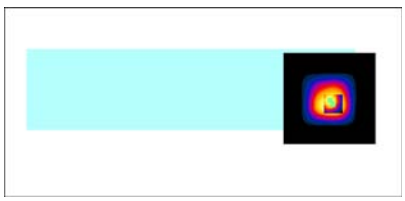
Coarse scan/z (axial) scan 50 x 50 (grid 10) with noise/ABM Interpolated Signal(x,y,z) (51x51x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1 = -6.18482 dB A/m
BWC Factor = 10.8 dB
Location: -2, 8, 363.7 mm

Fine scan/z (axial) scan 10 x 10 (grid 2) with noise/ABM Interpolated Signal(x,y,z) (51x51x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1 = 0.333487 dB A/m
BWC Factor = 10.8 dB
Location: -0.4, 5.8, 363.7 mm

Point scan (sinewave, max /z (axial) scan at point with noise/ABM Signal(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1 comp = 0.264188 dB A/m
BWC Factor = 0.00642518 dB
Location: -0.4, 5.8, 363.7 mm
Point scan (sinewave, max/z (axial) scan at point with noise/ABM Noise(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM2 = -33.3967 dB A/m
Location: -0.4, 5.8, 363.7 mm
Point scan (sinewave, max/z (axial) scan at point with noise/ABM SNR(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1/ABM2 = 33.6609 dB
BWC Factor = 0.00642518 dB
Location: -0.4, 5.8, 363.7 mm

Point scan (sinewave, z@earpiece)/z (axial) scan at point of earpiece with noise/ABM Signal(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1 comp = 0.0651276 dB A/m
BWC Factor = 0.00642518 dB
Location: 0, 5, 363.7 mm
Point scan (sinewave, z@earpiece)/z (axial) scan at point of earpiece with noise/ABM Noise(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM2 = -37.9172 dB A/m
Location: 0, 5, 363.7 mm
Point scan (sinewave, z@earpiece)/z (axial) scan at point of earpiece with noise/ABM SNR(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1/ABM2 = 37.9824 dB
BWC Factor = 0.00642518 dB
Location: 0, 5, 363.7 mm





Background noise 5mm above Grid Reference/z (axial) noise/ABM Noise(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM2 = -54.4343 dB A/m
Location: 0, 0, 368.7 mm

Date/Time: 2007-09-21 15:33:23
Test Laboratory: TCC Nokia
Type: RM-257; EUT: 12239; Serial: 004401/01/111749/2

Communication System: GSM1900
Frequency: 1880 MHz
Medium: Air
Medium parameters used: σ = 0 mho/m, ε_r = 1; ρ = 1 kg/m^3
Phantom section: AMB with Coil Section

DASY4 Configuration:
- Probe: AM1DV3 - 3036; Probe Notes: Sensitivity .007364 V / A/m - ; Calibrated: 2007-02-16
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn555; Calibrated: 2007-03-15
- Phantom: HAC Test Arch with Coil; Type: SD HAC P01 BA; Serial: 1004
- Measurement SW: DASY4, V4.7 Build 53; Postprocessing SW: SEMCAD, V1.8 Build 172

Point scan (sinewave, max)/z (axial) scan at point with noise/ABM Signal(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1 comp = 0.269518 dB A/m
BWC Factor = 0.00651198 dB
Location: -0.2, 5.8, 363.7 mm
Point scan (sinewave, max)/z (axial) scan at point with noise/ABM Noise(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM2 = -41.6387 dB A/m
Location: -0.2, 5.8, 363.7 mm
Point scan (sinewave, max)/z (axial) scan at point with noise/ABM SNR(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1/ABM2 = 41.9083 dB
BWC Factor = 0.00651198 dB
Location: -0.2, 5.8, 363.7 mm

Point scan (sinewave, z@earpiece)/z (axial) scan at point of earpiece with noise/ABM Signal(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1 comp = 0.0326317 dB A/m
BWC Factor = 0.00651198 dB
Location: 0, 5, 363.7 mm
Point scan (sinewave, z@earpiece)/z (axial) scan at point of earpiece with noise/ABM Noise(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM2 = -41.5713 dB A/m
Location: 0, 5, 363.7 mm
Point scan (sinewave, z@earpiece)/z (axial) scan at point of earpiece with noise/ABM SNR(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1/ABM2 = 41.604 dB
BWC Factor = 0.00651198 dB
Location: 0, 5, 363.7 mm

Background noise 5mm above Grid Reference/z (axial) noise/ABM Noise(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM2 = -42.7859 dB A/m
Location: 0, 0, 368.7 mm

Date/Time: 2007-09-24 09:55:37
Test Laboratory: TCC Nokia
Type: RM-257; EUT: 12239; Serial: 004401/01/111749/2

Communication System: WCDMA1700/2100
Frequency: 1732.4 MHz
Medium: Air
Medium parameters used: σ = 0 mho/m, ε_r = 1; ρ = 1 kg/m^3
Phantom section: AMB with Coil Section

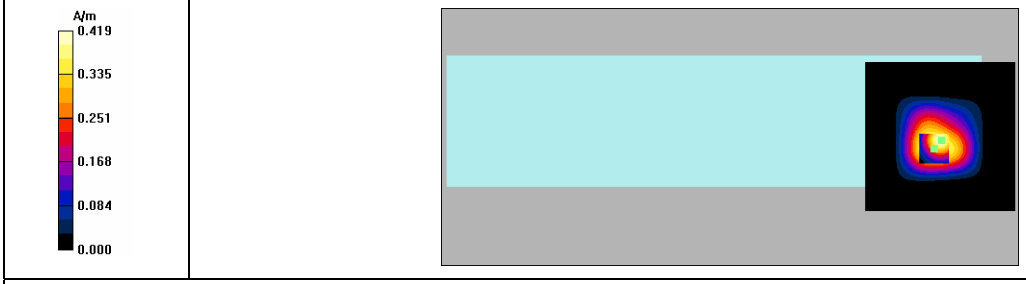
DASY4 Configuration:
- Probe: AM1DV3 - 3036; Probe Notes: Sensitivity .007364 V / A/m
- ; Calibrated: 2007-02-16
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn555; Calibrated: 2007-03-15
- Phantom: HAC Test Arch with Coil; Type: SD HAC P01 BA; Serial: 1004
- Measurement SW: DASY4, V4.7 Build 53; Postprocessing SW: SEMCAD, V1.8 Build 172

Coarse scan/z (axial) scan 50 x 50 (grid 10) with noise/ABM Interpolated Signal(x,y,z) (51x51x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1 = -7.56265 dB A/m
BWC Factor = 10.8 dB
Location: 2, 9, 363.7 mm

Fine scan/z (axial) scan 10 x 10 (grid 2) with noise/ABM Interpolated Signal(x,y,z) (51x51x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1 = -0.387685 dB A/m
BWC Factor = 10.8 dB
Location: -0.4, 6.2, 363.7 mm

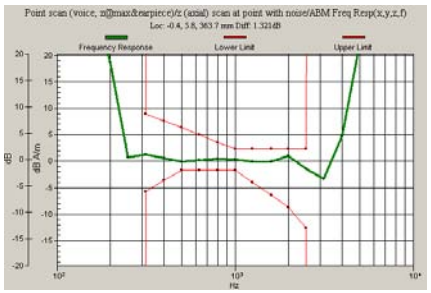
Point scan (sinewave, max)/z (axial) scan at point with noise/ABM Signal(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1 comp = -0.440513 dB A/m
BWC Factor = 0.00616479 dB
Location: -0.4, 6.2, 363.7 mm
Point scan (sinewave, max)/z (axial) scan at point with noise/ABM Noise(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM2 = -43.3884 dB A/m
Location: -0.4, 6.2, 363.7 mm
Point scan (sinewave, max)/z (axial) scan at point with noise/ABM SNR(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1/ABM2 = 42.9479 dB
BWC Factor = 0.00616479 dB
Location: -0.4, 6.2, 363.7 mm

Point scan (sinewave, max)/z (axial) scan at point of earpiece with noise/ABM Signal(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1 comp = -3.55659 dB A/m
BWC Factor = 0.00616479 dB
Location: 0, 5, 363.7 mm
Point scan (sinewave, max)/z (axial) scan at point of earpiece with noise/ABM Noise(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM2 = -44.0014 dB A/m
Location: 0, 5, 363.7 mm
Point scan (sinewave, max)/z (axial) scan at point of earpiece with noise/ABM SNR(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1/ABM2 = 40.4448 dB
BWC Factor = 0.00616479 dB
Location: 0, 5, 363.7 mm

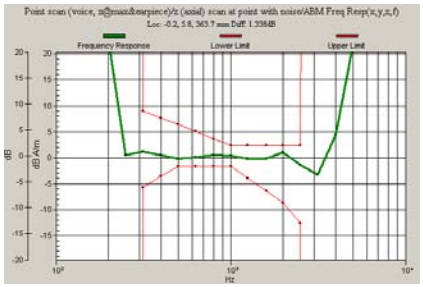


Background noise 5mm above Grid Reference/z (axial) noise/ABM Noise(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM2 = -43.8966 dB A/m
Location: 0, 0, 368.7 mm

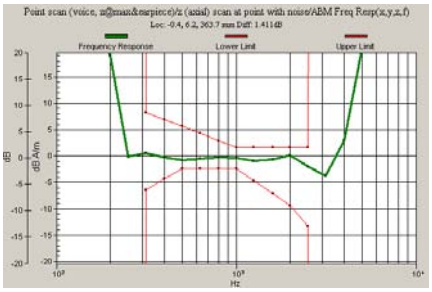
Frequency response in the point of maximum signal strength (axial)



GSM850

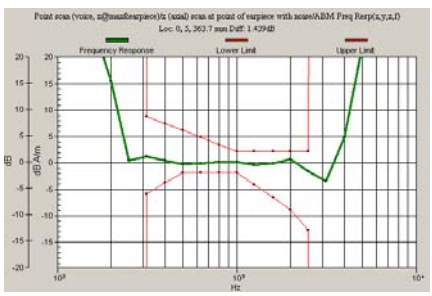


GSM1900

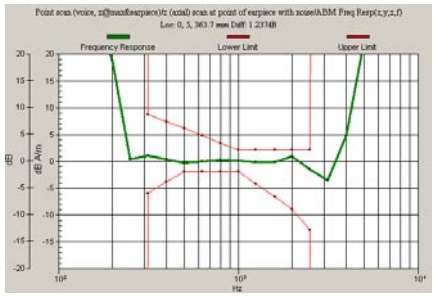


WCDMA1700/2100

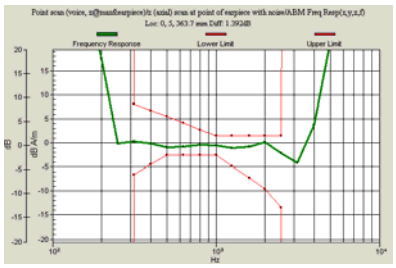
Frequency response over earpiece, point 0,5 (axial)



GSM850



GSM1900



WCDMA1700/2100

Date/Time: 2007-09-21 12:16:16
Test Laboratory: TCC Nokia
Type: RM-257; EUT: 12239; Serial: 004401/01/111749/2

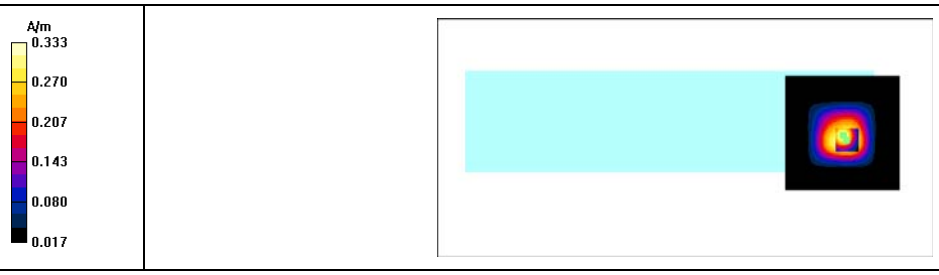
Communication System: GSM850
Frequency: 836.6 MHz
Medium: Air
Medium parameters used: $\sigma = 0$ mho/m, $\varepsilon_r = 1$; $\rho = 1$ kg/m^3
Phantom section: AMB with Coil Section

Coarse scan/x (longitudinal) scan 50 x 50 (grid 10) with noise/ABM Interpolated Signal(x,y,z) (51x51x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1 = -9.54791 dB A/m
BWC Factor = 10.8 dB
Location: 2, 8, 363.7 mm

Point scan (sinewave, max)/x (longitudinal) scan at point with noise/ABM Signal(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1 comp = -8.4214 dB A/m
BWC Factor = 0.00642518 dB
Location: 5.4, 6, 363.7 mm
Point scan (sinewave, max)/x (longitudinal) scan at point with noise/ABM Noise(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM2 = -33.7996 dB A/m
Location: 5.4, 6, 363.7 mm
Point scan (sinewave, max)/x (longitudinal) scan at point with noise/ABM SNR(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1/ABM2 = 25.3782 dB
BWC Factor = 0.00642518 dB
Location: 5.4, 6, 363.7 mm

DASY4 Configuration:
- Probe: AM1DV3 - 3036; Probe Notes: Sensitivity .007364 V / A/m - ; Calibrated: 2007-02-16
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn555; Calibrated: 2007-03-15
- Phantom: HAC Test Arch with Coil; Type: SD HAC P01 BA; Serial: 1004
- Measurement SW: DASY4, V4.7 Build 53; Postprocessing SW: SEMCAD, V1.8 Build 172

Fine scan/x (longitudinal) scan 10 x 10 (grid 2) with noise/ABM Interpolated Signal(x,y,z) (51x51x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1 = -8.31925 dB A/m
BWC Factor = 10.8 dB
Location: 5.4, 6, 363.7 mm



Background noise 5mm above Grid Reference/x (longitudinal) noise/ABM Noise(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM2 = -54.2556 dB A/m
Location: 0, 0, 368.7 mm

Date/Time: 2007-09-21 15:33:52
Test Laboratory: TCC Nokia
Type: RM-257; EUT: 12239; Serial: 004401/01/111749/2

Communication System: GSM1900
Frequency: 1880 MHz
Medium: Air
Medium parameters used: $\sigma = 0$ mho/m, $\varepsilon_r = 1$; $\rho = 1$ kg/m^3
Phantom section: AMB with Coil Section

Point scan (sinewave, max)/x (longitudinal) scan at point with noise/ABM Signal(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1 comp = -8.44931 dB A/m
BWC Factor = 0.00651198 dB
Location: 5.4, 6.2, 363.7 mm
Point scan (sinewave, max)/x (longitudinal) scan at point with noise/ABM Noise(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM2 = -35.6221 dB A/m
Location: 5.4, 6.2, 363.7 mm
Point scan (sinewave, max)/x (longitudinal) scan at point with noise/ABM SNR(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1/ABM2 = 27.1728 dB
BWC Factor = 0.00651198 dB
Location: 5.4, 6.2, 363.7 mm

DASY4 Configuration:
- Probe: AM1DV3 - 3036; Probe Notes: Sensitivity .007364 V / A/m - ; Calibrated: 2007-02-16
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn555; Calibrated: 2007-03-15
- Phantom: HAC Test Arch with Coil; Type: SD HAC P01 BA; Serial: 1004
- Measurement SW: DASY4, V4.7 Build 53; Postprocessing SW: SEMCAD, V1.8 Build 172

Background noise 5mm above Grid Reference/x (longitudinal) noise/ABM Noise(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM2 = -43.5907 dB A/m
Location: 0, 0, 368.7 mm

Date/Time: 2007-09-24 09:56:07
Test Laboratory: TCC Nokia
Type: RM-257; EUT: 12239; Serial: 004401/01/111749/2

Communication System: WCDMA1700/2100
Frequency: 1732.4 MHz
Medium: Air
Medium parameters used: σ = 0 mho/m, ε_r = 1; ρ = 1 kg/m^3
Phantom section: AMB with Coil Section

DASY4 Configuration:
- Probe: AM1DV3 - 3036; Probe Notes: Sensitivity .007364 V / A/m - ; Calibrated: 2007-02-16
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn555; Calibrated: 2007-03-15
- Phantom: HAC Test Arch with Coil; Type: SD HAC P01 BA; Serial: 1004
- Measurement SW: DASY4, V4.7 Build 53; Postprocessing SW: SEMCAD, V1.8 Build 172

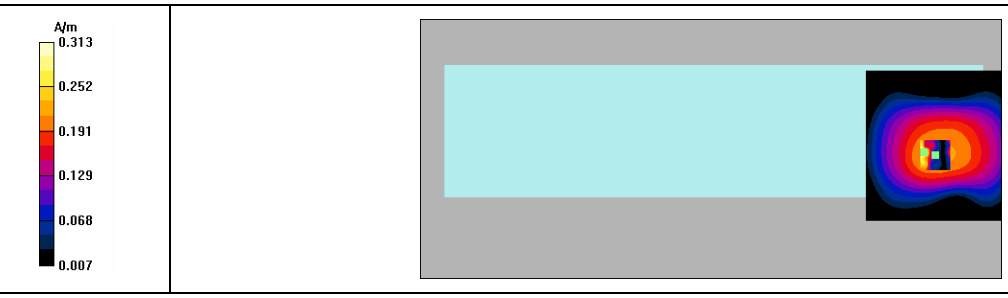
Coarse scan/x (longitudinal) scan 50 x 50 (grid 10) with noise/ABM Interpolated Signal(x,y,z) (51x51x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1 = -10.0935 dB A/m
BWC Factor = 10.8 dB
Location: 2, 8, 363.7 mm

Fine scan/x (longitudinal) scan 10 x 10 (grid 2) with noise/ABM Interpolated Signal(x,y,z) (51x51x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1 = -9.26932 dB A/m
BWC Factor = 10.8 dB
Location: 5.8, 7, 363.7 mm

Point scan (sinewave, max)/x (longitudinal) scan at point with noise/ABM Signal(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1 comp = -9.16593 dB A/m
BWC Factor = 0.00616479 dB
Location: 5.8, 7, 363.7 mm

Point scan (sinewave, max)/x (longitudinal) scan at point with noise/ABM Noise(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM2 = -50.886 dB A/m
Location: 5.8, 7, 363.7 mm

Point scan (sinewave, max)/x (longitudinal) scan at point with noise/ABM SNR(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1/ABM2 = 41.7201 dB
BWC Factor = 0.00616479 dB
Location: 5.8, 7, 363.7 mm



Background noise 5mm above Grid Reference/x (longitudinal) noise/ABM Noise(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM2 = -44.515 dB A/m
Location: 0, 0, 368.7 mm

Date/Time: 2007-09-21 11:39:08
Test Laboratory: TCC Nokia
Type: RM-257; EUT: 12239; Serial: 004401/01/111749/2

Communication System: GSM850
Frequency: 836.6 MHz
Medium: Air
Medium parameters used: $\sigma = 0$ mho/m, $\varepsilon_r = 1$; $\rho = 1$ kg/m^3
Phantom section: AMB with Coil Section

DASY4 Configuration:
- Probe: AM1DV3 - 3036; Probe Notes: Sensitivity .007364 V / A/m
- ; Calibrated: 2007-02-16
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn555; Calibrated: 2007-03-15
- Phantom: HAC Test Arch with Coil; Type: SD HAC P01 BA; Serial: 1004
- Measurement SW: DASY4, V4.7 Build 53; Postprocessing SW: SEMCAD, V1.8 Build 172

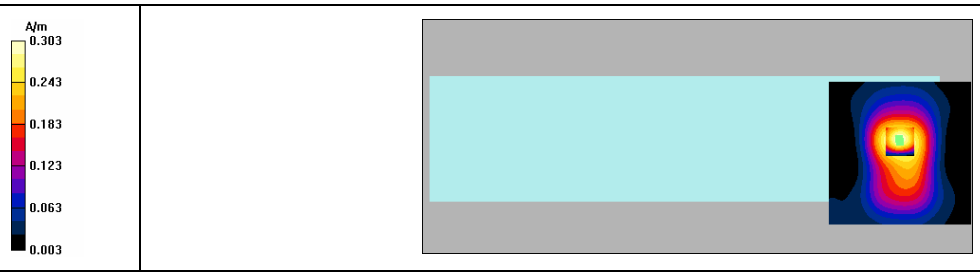
Coarse scan/y (transversal) scan 50 x 50 (grid 10) with noise/ABM Interpolated Signal(x,y,z) (51x51x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1 = -10.3783 dB A/m
BWC Factor = 10.8 dB
Location: 0, 1, 363.7 mm

Fine scan/y (transversal) scan 10 x 10 (grid 2) with noise/ABM Interpolated Signal(x,y,z) (51x51x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1 = -8.17686 dB A/m
BWC Factor = 10.8 dB
Location: 0.4, 0.2, 363.7 mm

Point scan (sinewave, max)/y (transversal) scan at point with noise/ABM Signal(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1 comp = -8.22574 dB A/m
BWC Factor = 0.00642518 dB
Location: 0.4, 0.2, 363.7 mm

Point scan (sinewave, max)/y (transversal) scan at point with noise/ABM Noise(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM2 = -31.027 dB A/m
Location: 0.4, 0.2, 363.7 mm

Point scan (sinewave, max)/y (transversal) scan at point with noise/ABM SNR(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1/ABM2 = 22.8013 dB
BWC Factor = 0.00642518 dB
Location: 0.4, 0.2, 363.7 mm



Background noise 5mm above Grid Reference/y (transversal) noise/ABM Noise(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM2 = -54.3376 dB A/m
Location: 0, 0, 368.7 mm

Date/Time: 2007-09-21 15:34:28
Test Laboratory: TCC Nokia
Type: RM-257; EUT: 12239; Serial: 004401/01/111749/2

Communication System: GSM1900
Frequency: 1880 MHz
Medium: Air
Medium parameters used: σ = 0 mho/m, ε_r = 1; ρ = 1 kg/m^3
Phantom section: AMB with Coil Section

Point scan (sinewave, max)/y (transversal) scan at point with noise/ABM Signal(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1 comp = -8.24777 dB A/m
BWC Factor = 0.00651198 dB
Location: 0.4, 0, 363.7 mm
Point scan (sinewave, max)/y (transversal) scan at point with noise/ABM Noise(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM2 = -32.9604 dB A/m
Location: 0.4, 0, 363.7 mm
Point scan (sinewave, max)/y (transversal) scan at point with noise/ABM SNR(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1/ABM2 = 24.7127 dB
BWC Factor = 0.00651198 dB
Location: 0.4, 0, 363.7 mm

DASY4 Configuration:
- Probe: AM1DV3 - 3036; Probe Notes: Sensitivity .007364 V / A/m - ; Calibrated: 2007-02-16
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn555; Calibrated: 2007-03-15
- Phantom: HAC Test Arch with Coil; Type: SD HAC P01 BA; Serial: 1004
- Measurement SW: DASY4, V4.7 Build 53; Postprocessing SW: SEMCAD, V1.8 Build 172

Background noise 5mm above Grid Reference/y (transversal) noise/ABM Noise(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM2 = -42.0879 dB A/m
Location: 0, 0, 368.7 mm

Date/Time: 2007-09-24 09:56:43
Test Laboratory: TCC Nokia
Type: RM-257; EUT: 12239; Serial: 004401/01/111749/2

Communication System: WCDMA1700/2100
Frequency: 1732.4 MHz
Medium: Air
Medium parameters used: σ = 0 mho/m, ε_r = 1; ρ = 1 kg/m^3
Phantom section: AMB with Coil Section

DASY4 Configuration:
- Probe: AM1DV3 - 3036; Probe Notes: Sensitivity .007364 V / A/m
- ; Calibrated: 2007-02-16
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn555; Calibrated: 2007-03-15
- Phantom: HAC Test Arch with Coil; Type: SD HAC P01 BA; Serial: 1004
- Measurement SW: DASY4, V4.7 Build 53; Postprocessing SW: SEMCAD, V1.8 Build 172

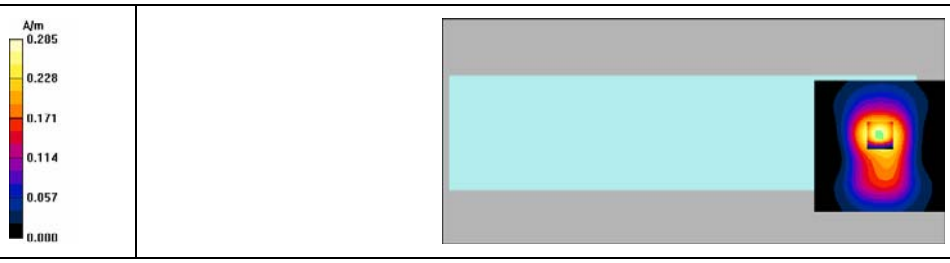
Coarse scan/y (transversal) scan 50 x 50 (grid 10) with noise/ABM Interpolated Signal(x,y,z) (51x51x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1 = -10.9037 dB A/m
BWC Factor = 10.8 dB
Location: 0, 1, 363.7 mm

Fine scan/y (transversal) scan 10 x 10 (grid 2) with noise/ABM Interpolated Signal(x,y,z) (51x51x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1 = -8.81982 dB A/m
BWC Factor = 10.8 dB
Location: 0.6, 0.4, 363.7 mm

Point scan (sinewave, max)/y (transversal) scan at point with noise/ABM Signal(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1 comp = -8.79044 dB A/m
BWC Factor = 0.00616479 dB
Location: 0.6, 0.4, 363.7 mm

Point scan (sinewave, max)/y (transversal) scan at point with noise/ABM Noise(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM2 = -28.7275 dB A/m
Location: 0.6, 0.4, 363.7 mm

Point scan (sinewave, max)/y (transversal) scan at point with noise/ABM SNR(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM1/ABM2 = 19.9371 dB
BWC Factor = 0.00616479 dB
Location: 0.6, 0.4, 363.7 mm



Background noise 5mm above Grid Reference/y (transversal) noise/ABM Noise(x,y,z) (1x1x1):
Measurement grid: dx=10mm, dy=10mm
Cursor:
ABM2 = -42.4459 dB A/m
Location: 0, 0, 368.7 mm

APPENDIX B: AUDIO MAGNETIC PROBE AM1DV3 S/N 3036 CALIBRATION DOCUMENT

Schmid & Partner Engineering AG

s p e a g

Zeughausstrasse 43, 8004 Zurich, Switzerland
Phone +41 1 245 9700, Fax +41 1 245 9779
info@speag.com, http://www.speag.com

Client **Nokia Salo TCC**

Certificate of test and configuration

Item	**AM1DV3** Audio Magnetic 1D Field Probe
Type No	SP AM1 001 BA
Series No	**3036**
Manufacturer / Origin	Schmid & Partner Engineering AG, Zürich, Switzerland

Description of the item
The Audio Magnetic Field Probe is a fully shielded magnetic field probe for the frequency range from 100 Hz to 20 kHz. The pickup coil is compliant with the dimensional requirements of [1]. The probe includes a symmetric 20dB low noise amplifier for the signal available at the shielded 3 pin connector at the side. Power is supplied via the same connector (phantom power supply) and monitored via the LED near the connector. The 7 pin connector at the end of the probe does not carry any signals, but determines the angle of the sensor when mounted on the DAE. The probe supports mechanical detection of the surface. The single sensor in the probe is arranged in a tilt angle allowing measurement of 3 orthogonal field components when rotating the probe by 120° around its axis. It is aligned with the perpendicular component of the field, if the probe axis is tilted 35.3° above the measurement plane, using the connector rotation and Sensor angle stated below.
The probe is fully RF shielded when operated with the matching signal cable (shielded) and allows measurement of audio magnetic fields in the close vicinity of RF emitting wireless devices according to [1] without additional shielding.

Handling of the item
The probe is manufactured from stainless steel. In order to maintain the performance and calibration of the probe, it must not be opened. The probe is designed for operation in air and shall not be exposed to humidity or liquids. For proper operation of the surface detection and emergency stop functions in the DASY4 system, the probe must be operated with the special probe cup provided (larger diameter). Verify that the probe can slide in the probe cup rubber smoothly.

Functional test, configuration data and sensitivity
The probe configuration data were evaluated after a functional test including noise level and RF immunity. Connector rotation, sensor angle and sensitivity are specific for this probe.

DASY4 configuration data for the probe

Configuration item	Condition	Configuration Data	Dimension
Overall length	mounted on DAE in DASY4 system	296	mm
Tip diameter	at the cylindrical part	6	mm
Sensor offset	center of sensor, from tip	3	mm
Connector rotation	Evaluated in homogeneous 1 kHz magnetic field generated with AMCC Helmholtz Calibration Coil	**-5.0**	°
Sensor angle		**1.31**	°
Sensitivity	at 1 kHz	**0.007364**	V / (A/m)

Standards [1] ANSI-C63.19-2006

Test date 16.02.2007 MM / FB

Issue date 16.02.2007

Signature